Complete if Known Substitute for form 1449A/PTO New Divisional Application Application Number INFORMATION DISCLOSURE based on USSN: 09/755,173-STATEMENT BY APPLICANT July 16, 2003 Filing Date (use as many sheets as necessary) David M. Krinsky et al. First Named Inventor 2634 Art Unit Kevin Kim Examiner Name of Sheet Attorney Docket Number 081513-334

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Exeminer Initials	Cite No.	U.S. Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where	
		Number - Kind Code ((f known)			Relevant Passages or Relevant Figures Appear	
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		OTHER PRIOR	ART - NON PATENT	LITERATURE DOCUMENTS		
Examiner Initials	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.)., date, page(s), volume-issue number(s), publisher, city and/or country where published.				
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Examiner Signature	/Khanh Tran/	(10/27/2006)	Date Considered
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